

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/665,566	TAJIIKA, YOSUKE	
	Examiner Sunray Chang	Art Unit 2121	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,108,748	08-2000	Ofek et al.	711/112
*	B	US-6,133,938	10-2000	James, David V.	725/80
*	C	US-6,381,507	04-2002	Shima et al.	700/83
*	D	US-6,564,245	05-2003	Fukasawa et al.	709/205
*	E	US-6,839,670	01-2005	Stammier et al.	704/251
*	F	US-2002/0184457	12-2002	Yuasa et al.	711/161
*	G	US-2004/0030560	02-2004	Takami et al.	704/275
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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